The Crystal Structures of Rh₂Si and Rh₅Si₃ with some Notes on the Rh-Si System

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The crystal structures of $\mathrm{Rh_2Si}$ and $\mathrm{Rh_5Si_3}$ have been refined from single crystal data. For $\mathrm{Rh_2Si}$ (C23 type), the unit cell dimensions are $a=5.40_8$ Å, $b=3.93_0$ Å, and $c=7.38_3$ Å, and the atomic parameters are $\mathrm{Rh_1}$ in 4(c): x=0.8393, z=0.0694; $\mathrm{Rh_{II}}$ in 4(c): x=0.9728, z=0.6991; Si in 4(c): x=0.2819, z=0.1052. For $\mathrm{Rh_5Si_3}$ ($\mathrm{Rh_5Ge_3}$ -type) the unit cell dimensions are $a=5.31_7$ Å, $b=10.13_1$ Å and $c=3.89_5$ Å, and the atomic parameters are $\mathrm{Rh_I}$ in 2(c); $\mathrm{Rh_{II}}$ in 4(g): x=0.1542, y=0.2158; $\mathrm{Rh_{III}}$ in 4(h): x=0.3297, y=0.3936; $\mathrm{Si_I}$ in 2(a); $\mathrm{Si_{II}}$ in 4(h): x=0.3917, y=0.1505. A hexagonal phase with the composition $\mathrm{Rh_{\sim 1.6}Si}$ and the unit cell dimensions $a=11.85_1$ Å, $c=3.62_3$ Å is reported. The crystal structures of Rh₂Si and Rh₅Si₃ have been refined from

An investigation of the silicides of the platinum metals has recently been reported by Finnie¹, and the results for the rhodium-silicon system are in good agreement with those of the earlier investigation of Bhan and Schubert 2. A further examination of the rhodium-silicon system has been made at this Institute and some new results have been obtained.

The present paper gives an account of some phase-analytical observations, and in addition the results of the crystal structure refinements of Rh, Si and Rh₅Si₃ are reported. The formation of these intermediate phases was reported earlier by Aronsson et al.³ (Rh₂Si) and Bhan and Schubert ² (Rh₅Si₃).

EXPERIMENTAL

Powder diffraction examination. Alloys were prepared by arc-melting rhodium metal powder (Heraeus, claimed purity 99.9%) and silicon powder (Pechiney and Cie, claimed purity 99.9%). The arc-melted alloys were annealed in evacuated and sealed silica tubes at 1100°C for 8-14 days. Powder photographs were recorded in Guinier cameras using $CuK\alpha$ -radiation with silicon ($\alpha = 5.4305$ Å) as an internal calibration standard. The lattice parameters are accurate to about 0.1%.

Single crystal examination. Diffraction patterns were recorded in a Weissenberg camera using Nb-filtered MoK-radiation. The multiple film technique was used with thin iron foil interleaved between successive films. The intensities of the X-ray reflections were

estimated visually by comparison with a standard intensity scale.

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Table 1. Phase analytical observations on the Rh-Si system at 1100°C.

	Ref.	9	63		
Unit cell dimensions (in Å)	Literature data	Rh: $a = 3.8044$ (for pure rhodium) 9 Rh ₂ Si: $a = 5.40_8$, $b = 3.93_0$, $c = 7.38_3$ 1,2,3	$\mathrm{Rh_5Si_3}\colon a=5.30_{\mathfrak{b}},\ b=10.07_{4},\ c=3.88_{\mathfrak{s}}$		
Unit cell	This work (estimated accuracy \pm 0.1 %)	Rh(Si) and $a = 3.80_5$ Rh ₂ Si $a = 5.41_3$, $b = 3.93_1$, $c = 7.38_4$	$a = 5.41_0, b = 3.93_0, c = 7.38_8$ $a = 5.31_7, b = 10.12_4, c = 3.90_2$	a = 5.31, $b = 10.12$ 4, $c = 3.90$ 2 a = 11.851, $c = 3.62$ 3	$a = 11.85_1$, $c = 3.62_3$
	Observed	Rh(Si) and Rh ₂ Si	Rh ₂ Si and Rh ₅ Si ₃	Rh ₅ Si ₃ and Rh _{1.5} Si	Rh _{1.5} Si *
Nominal	composition of alloy	$\mathrm{Rh}_{2.0}\mathrm{Si}_{0.9}$	$\mathrm{Rh}_{2.2}\mathrm{Si}_{1.1}$	Rh _{2.0} Si _{1.4}	Rh _{2.0} Si _{1.7}

* Additional lines in the powder pattern indicated the presence of small amounts of another phase, the structure of which did not belong to any of the RhSi modifications (B2, B20, B31) reported.

For the refinement of Rh_2Si a single crystal fragment was selected from an arc-melted alloy annealed at $1100^{\circ}C$ for 14 days. A powder photograph of the alloy showed weak reflections from Rh_2Si_3 in addition to reflections from Rh_2Si . Single crystal diffraction patterns were obtained with the [010] direction as the rotation axis and the zero layer was recorded. The intensities of 164 non-equivalent h0l reflections were measured. The 22 strongest reflections were omitted from the refinement because of extinction effects and are not included in the final R value quoted below.

Crystals of $\mathrm{Rh_5Si_3}$ obtained from arc-melted and sintered alloys were too small for use in a single crystal examination. Crystals were therefore prepared by heating a near single-phase alloy of $\mathrm{Rh_5Si_3}$ in an induction furnace at $\sim 1200^\circ\mathrm{C}$ for 4 h. A powder pattern of the product showed that small amounts of a phase, here referred to as $\mathrm{Rh_{1.5}Si}$, were also present. All powder patterns of samples containing $\mathrm{Rh_5Si_3}$ and prepared at $1200^\circ\mathrm{C}$ demonstrated line-broadening effects and the unit cell dimensions do not have an accuracy better than $\pm~0.1~\%$. Single crystal patterns were obtained with the [001] direction as the rotation axis and the zero layer was recorded. The structure was refined from 120 non-equivalent F(hk0)-values.

Structure refinement. The atomic scattering factor tables given for Rh by Thomas and Umeda 5 and for Si by Tomiie and Stam 6 were used. The real part of the dispersion correction factor according to Dauben and Templeton 7 was included in the structure factor calculations.

The Lorentz and polarisation factor corrections, the structure factor calculations and the calculations of interatomic distances were carried out on the electronic digital computer BESK, with programmes available at BESK. Atomic parameters and individual isotropic temperature factors were refined using a least squares programme ¹⁴ for crystal structure refinements on the electronic digital computer FACIT. A weighting scheme

Table 2. X-Ray powder data for Rh₂Si. (Guinier-type camera, CuKα-radiation).

hkl	${ m sin^2}\Theta_{ m obs}$	$\sin^2\!\Theta_{ m calc}$	$I_{ m obs}$	$p F ^2_{ m calc} imes 10^{-3}$
101	0.0310	0.0312	w — —	1.6
002		0.0436		0.4
011	0.0494	0.0494	m	11.4
102	0.0639	0.0639	m	20.3
111	0.0697	0.0697	$\operatorname{\mathbf{st}}$	41.9
200		0.0813	w	2.6
201	-	0.0922	_	1.2
112	0.1023	0.1023	$\operatorname{st}+$	131.3
103	0.1184	0.1184	$\operatorname{\mathbf{st}}$	$\boldsymbol{65.3}$
210	0.1196	0.1198	$\operatorname{st}+$	125.5
202	0.1249	0.1249	$\operatorname{\mathbf{st}}$	82.5
211	0.1306	0.1307	$\operatorname{st}+$	203.8
013	0.1364	0.1366	$\operatorname{st}+$	211.2
020	0.1537	0.1539	• st	161.7
113	0.1568	0.1569	w	$\boldsymbol{27.0}$
212		0.1634		13.8
004	_	0.1744		0.4
203	0.1794	0.1794	\mathbf{m}	78.5
121	_	0.1851	-	1.9
301	0.1937	0.1938	m	62.3
104	_	0.1947		16.5
$\boldsymbol{022}$	-	0.1975	-	0.5
(122	0.2178	$\int 0.2178$	w	(25.5
1213		0.2179	w	1.2
302	0.2263	0.2265	w —	18.4
311		0.2323		1.6
114	0.2329	0.2332	w —	$\boldsymbol{20.2}$
220	_	0.2352		3.3
221	-~-	0.2461		1.6
204	0.2557	0.2557	w	15.6
312	_	0.2650	-	0.8
123	0.2723	0.2723	\mathbf{m}	86.7
$\boldsymbol{222}$	0.2788	0.2788	$^{\mathrm{m}+}$	110.5
303	-	0.2810		7.0
105	0.2927	0.2928	$\mathbf{w}+$	67.7
214		0.2942	_	2.0

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Table 3. X-Ray powder data for Rh₅Si₃. (Guinier-type camera, CuKα-radiation).

hkl	$\sin^2\!\Theta_{ m obs}$	$\sin^2\!\Theta_{ m calc}$	$I_{ m obs}$	$p F ^2_{ m calc} imes 10^{-1}$
020		0.0232		0.8
110	_	0.0268		0
001	0.0390	0.0390	w	6.1
120	0.0442	0.0442	w	10.9
021	0.0622	0.0622	w —	15.0
111	0.0659	0.0659	m	41.5
130	0.0733	0.0732	\mathbf{m}	41.0
121	0.0831	0.0833	${f st}$	171.7
200	_	0.0841	-	1.7
210	-	0.0899	_	2.4
040	_	0.0928		1.2
220	0.1069	0.1073	w	49.4
131	0.1122	0.1122	\mathbf{m}	71.4
140	0.1141	0.1138	m	90.7
201	0.1231	0.1231	w	40.4
211	0.1290	0.1289	$\mathbf{st}+$	373.9
041	0.1319	0.1318	$\mathbf{st} +$	391.4
230	0.1365	0.1363	m —	170.2
221	0.1464	0.1463	m —	159.3
141		0.1528		2.2
002	0.1558	0.1562	m	268.4
150	_	0.1660	_	7.1
231		0.1753		1.1
240	0.1772	0.1769	w	$\boldsymbol{42.2}$
022		0.1794		1.0
112	_	0.1830	_	0
310	0.1947	0.1950	w	95.0
122		0.2004		13.9
151		0.2050		41.6
060	_	0.2087		0.1
320		0.2124		8.5
241	_	0.2159	_	0.2
(250)		(0.2290)		(40.7
{ 132	0.2298	$\{0.2294$	m —	₹ 53.0
l 160		0.2298		(99.0
311		0.2341		2.1
202	month.	0.2403		2.3
330		0.2414	take Film	14.4
212	_	0.2461		3.2
042	_	0.2489		1.6
321	_	0.2514		3.9
222	0.2634	0.2634	w — —	66.0
251	_	0.2681		0
161	manus.	0.2688	_	4.6
142	0.2698	0.2700	w	122.2
331		0.2804		0.6
340	_	0.2820		3.9
(232	0.2927	(0.2924)	m	1234.7
(260		$\{0.2928$		59.0
		•		

according to Cruickshank ⁸, w = $1/(a + |F_o| + c|F_o|^2)$ was used in the final stages of the refinements. The constants a and c were approximately equal to $2|F_{o,\min}|$ and $2/|F_{o,\max}|$, respectively.

Table 4. Observed X-ray powder data for $Rh_{1.5}Si.$ (Guinier-type camera, $CuK\alpha$ -radiation).

hkl	$\sin^2\!\Theta_{ m obs}$	$\sin^2\!\boldsymbol{\Theta}_{ m calc}$	$I_{ m obs}$
110	0.0169	0.0169	w
210	0.0394	0.0395	w
${300 \atop 101}$	0.0508	${0.0508 \atop 0.0509}$	\mathbf{st}
111	0.0623	0.0622	w
${220 \choose 201}$	0.0678	$\left\{ egin{matrix} 0.0677 \ 0.0679 \end{matrix} ight.$	w
310	0.0732	0.0734	$\mathbf{w} +$
211	0.0847	0.0848	$\mathbf{w} +$
400	0.0900	0.0903	w
320	0.1071	0.1071	$\mathbf{w} +$
221	0.1129	0.1130	$\mathbf{m} +$
${410 \atop 311}$	0.1185	${0.1185 \atop 0.1186}$	$\operatorname{st}+$
`401	0.1353	0.1355	$\mathbf{m} +$
500	0.1407	0.1410	w
${330 \atop 321}$	0.1522	$\left\{ egin{array}{l} 0.1523 \ 0.1525 \end{array} ight.$	m
`411	0.1635	0.1637	w — —
510	0.1747	0.1749	$\mathbf{w} +$
002	0.1814	0.1812	m
501	0.1858	0.1863	w
331	0.1975	0.1976	\mathbf{w} —
₍ 511		(0.2201	
{ 5 2 0	0.2198	$\{0.2200$	w
(212		0.2206	
610	0.2417	0.2426	w
${ 431 \atop 312}$	0.2542	$ \begin{cases} 0.2540 \\ 0.2545 \end{cases} $	\mathbf{w}
${440 \atop 402}$	0.2704	$\left\{ egin{matrix} 0.2708 \\ 0.2714 \end{smallmatrix} ight.$	w
700	0.2763	0.2764	w
520 ∫ 611	0.2888	(0.2878	w
322		0.2883	vv
620	0.2934	0.2934	\mathbf{w} —
412	0.2997	0.2996	m+

RESULTS AND DISCUSSION

Some notes on the Rh-Si system. The unit cell dimensions obtained for metal-rich phases in two-phase regions of the Rh-Si system are given in Table 1. It can be seen from the table that the edge of the cubic unit cell for Rh(Si) does not differ significantly from that given for pure rhodium $(a=3.8044~\text{Å})^9$. This indicates that the solubility of silicon in rhodium is very small. The table shows that there is no appreciable variation in the cell dimensions of Rh_2Si and Rh_5Si_3 and it is concluded that at the temperature of preparation the homogeneity range of each phase is narrow. The cell dimensions are also in good agreement with those in earlier publications.

Table 5. Interatomic distances in Rh₂Si. (Distances shorter than 3.75 Å are listed).

At the nominal composition Rh_{~1.5}Si a new intermediate phase was found. Powder and single crystal data showed that the symmetry is hexagonal, and the unit cell dimensions are given in Table 1. The structure of the new phase has not yet been determined. It should be noted, however, that the a-axis is three times that reported by Bhan and Schubert ² for Rh₃Si₂₊ (B8-type). X-Ray powder data for Rh₂Si, Rh₅Si₃ and Rh_{1.5}Si are presented in Tables

2-4. Only diffraction lines for which $\sin^2\theta < 0.30$ are given.

Table 6. Interatomic distances in Rh, Si, (Distances shorter than 4 Å are listed).

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- 2 Rh<sub>I</sub>
Rh_{T}
                     : 3.895
        \begin{array}{lll} -& 4 & \mathrm{Rh_{II}} & : 2.85_{2}(2), \ 2.99_{8}(2) \\ -& 4 & \mathrm{Rh_{III}} & : 2.83_{5} \end{array}
        - 2 Si_{I}
                     \begin{array}{c} 1 & 2.66 \\ \vdots & 2.53 \end{array}
        - 4 Si<sub>II</sub>
Rh_{III} = 2 Rh_{I} : 2.83_{5} 
 - 4 Rh_{II} : 2.81_{5}(2), 2.82_{6}(2)
       - 2 Rh<sub>I</sub> : 2.66
Si_{T}
        -4 Rh_{II} : 2.33(2), 3.42(2)
        -4 \text{ Rh}_{III}^{II}: 2.40
        -2 \text{ Rh}_{\text{I}} : 2.53
Si_{II}
       -4 \text{ Rh}_{\text{II}} : 2.41(2), 2.76(2)
        -4 \text{ Rh}_{\text{III}}^{11}: 2.37, 2.49, 2.85, 3.02
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The structure determinations of Rh_2Si and Rh_5Si_3 . The structure type for Rh_2Si was verified from comparison with the data for Ru_2Si^4 and nothing was found during the refinement of the structure that contradicted the choice of the space-group Pnma.

From the observed intensity data for Rh₅Si₃ it was evident that the structure-type proposed earlier ² was correct. During the refinement of the structure there was nothing which indicated that a space-group other than *Pbam* should be chosen.

The results of the structure determinations are given below. Interatomic distances are listed in Tables 5 and 6.

 Rh_2Si

Space-group: $Pnma~(D_{2h}^{16}),~Z=4~($ Structure type C 23). $a=5.40_8~\text{Å},~b=3.93_0~\text{Å},~c=7.38_3~\text{Å},~U=156.9~\text{Å}^3.$

Atom	Position					Isotropic t	emp.factor
		\boldsymbol{x}	$\sigma(x)$	z	$\sigma(z)$	B	$\sigma(B)$
$rac{\mathrm{Rh_{II}}}{\mathrm{Si}}$	$egin{array}{c} {\bf 4}(c) \ {\bf 4}(c) \ {\bf 4}(c) \end{array}$	$0.8393 \\ 0.9728 \\ 0.2819$	$0.0004 \\ 0.0004 \\ 0.0018$	$0.0694 \\ 0.6991 \\ 0.1052$	$\begin{array}{c} 0.0003 \\ 0.0003 \\ 0.0011 \end{array}$	$\begin{array}{c} 0.42 \\ 0.36 \\ 0.6 \end{array}$	$0.02 \\ 0.02 \\ 0.1$

Final R-value = 0.093.

 Rh_5Si_3

Space-group: $Pbam\ (D_{2h}^9),\ Z=2,\ (Structure\ type\ Rh_5Ge_3).\ a=5.31,\ Å,\ b=10.13,\ Å,\ c=3.89,\ Å,\ U=209.8\ Å^3.$

Atom	Position					Isotropic t	emp.factor
		\boldsymbol{x}	$\sigma(x)$	y	$\sigma(y)$	B	$\sigma(B)$
$egin{array}{l} \mathbf{Rh_I} \\ \mathbf{Rh_{II}} \\ \mathbf{Rh_{III}} \\ \mathbf{Si_I} \\ \mathbf{Si_{II}} \end{array}$	$egin{array}{c} 2(c) \ 4(g) \ 4(h) \ 2(a) \ 4(h) \end{array}$	$0.1542 \\ 0.3297 \\ - \\ 0.3917$	0.0006 0.0007 0.0025	$0.2158 \\ 0.3936 \\ - \\ 0.1505$	$0.0004 \\ 0.0004 \\ 0.0015$	$egin{array}{c} 0.23 \\ 0.12 \\ 0.27 \\ 0.5 \\ 0.6 \\ \end{array}$	$0.06 \\ 0.04 \\ 0.04 \\ 0.3 \\ 0.2$

Final R-value = 0.074

Discussion. The structure types exhibited by Rh₂Si and Rh₅Si₃ have been discussed earlier by Geller ¹⁰, in connection with the isomorphous germanides, Rh₂Ge and Rh₅Ge₃. A comparison of the interatomic distances in these isomorphous silicides and germanides is given in Table 7. The average Rh—Rh distances listed in the table are nearly equal for the silicides and the germanides and are appreciably greater than the Goldschmidt metal diameter. The difference between the average Rh—Ge and Rh—Si distances is about 0.05 Å, which is equal to the difference between the tetrahedral covalent radii for germanium

Table 7. Comparison of interatomic distances in $\mathrm{Rh_2Si}$, $\mathrm{Rh_2Ge}$, $\mathrm{Rh_5Si_3}$ and $\mathrm{Rh_5Ge_3}$

Compound	${ m Rh-Rh}$ distances	Average distances
$\mathrm{Rh}_{2}\mathrm{Si}$	$ m Rh_{II} - 8 \ Rh: \ 2.76(2), \ 2.80(2), \ 2.80, \ 2.82(2), \ 2.83 \ Rh_{II} - 8 \ Rh: \ 2.76(2), \ 2.80(2), \ 2.80, \ 2.81(2), \ 2.83 \ m$	2.80 2.80
$\mathrm{Rh}_{2}\mathrm{Ge}$	$egin{array}{cccccccccccccccccccccccccccccccccccc$	$\frac{2.83}{2.81}$
$\mathrm{Rh}_5\mathrm{Si}_3$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	2.88 2.83 2.83
$\mathrm{Rh}_{5}\mathrm{Ge}_{3}$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	2.93 2.84 2.84
	Rh-Si and Rh-Ge distances	
$\mathrm{Rh}_{2}\mathrm{Si}$	Si — 10 Rh: 2.41, 2.42, 2.44(2), 2.47(2), 2.47, 2.80(2), 3.03	2.58
$ m Rh_2Ge$	Ge — 10 Rh: 2.46, 2.47, 2.49(2), 2.50(2), 2.57, 2.83(2), 3.00	2.61
$\mathrm{Rh_5Si_3}$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	2.45 2.61
$\mathrm{Rh_5Ge_3}$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	$\frac{2.51}{2.66}$

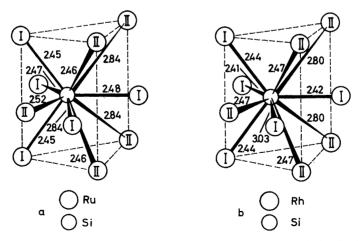


Fig. 1. The environment of the Si atom in Ru₂Si (a) and Rh₂Si (b).

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and silicon. (It should be pointed out that the value of 2.44 Å given by Geller for one of the Rh—Ge distances in Rh_5Si_3 is incorrect. The correct value is 3.06 Å).

The interatomic distances in Rh_2Si are similar to those found in other phases with the C23 structure type. There are some differences in detail, however. In Ru_2Si the silicon atoms are surrounded by ten ruthenium atoms at distances between 2.45-2.84 Å, (see Fig. 1a), while in Rh_2Si the silicon atoms have nine metal atoms at distances between 2.41-2.80 Å and the tenth at a distance of 3.03 Å (Fig. 1b). A similar tendency for a reduction in the number of close metal neighbours about silicon is also found on passing from Co_2Si ¹¹ to Ni_2Si (C23-type) ¹².

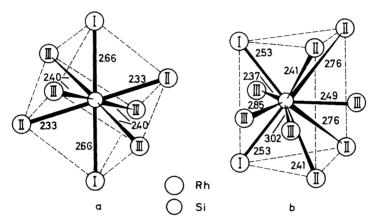


Fig. 2. The environment of the Si_I atom in Rh₅Si₃ (a) and the environment of the Si_{II} atom in Rh₅Si₃ (b). (The Roman numerals refer to the notations for the different crystallographic positions of the metal atoms).

The present work has shown that the interatomic distances in Rh₂Si and the alleged Rh₂B-phase are identical within the limits of experimental error. This supports the suggestion made by Aronsson *et al.*³ that the Rh₂B crystals studied by Mooney and Welch ¹³ were in fact crystals of Rh₂Si.

With regard to the form of the coordination polyhedron and the Rh—Si interatomic distances, the environment of the Si_{II} atoms in Rh₅Si₃ (Fig. 2b) is similar to that of the Si atoms in Rh₂Si. The Si_I atoms in Rh₅Si₃ (Fig. 2a) have a slightly distorted cubic environment of metal atoms.

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